


<b>Search Notes</b>  	<b>Application/Control No.</b>  10717496	<b>Applicant(s)/Patent Under Reexamination</b>  SAINT ETIENNE ET AL.
	<b>Examiner</b>  Cehic, Kenan	<b>Art Unit</b>  2616

SEARCHED			
Class	Subclass	Date	Examiner
370	516,517,519,238,395,21,253,235,230,230.1,508,516,389	11/8/2007	KC
370	235,252	5/23/2008	kc

SEARCH NOTES		
Search Notes	Date	Examiner
Inventorship Search	11/5/2007	KC
Consulted with SPE Kwang Yao	11/7/2007	KC
EAST Text search	11/6/2007	KC
IEEE Xplorer	11/8/2007	KC
Consulted with SPE Kwang Yao	5/23/2008	kc
Update Search	5/23/2008	kc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	See Interference Search printout		